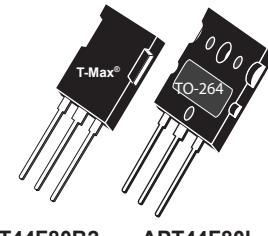


N-Channel FREDFET

Power MOS 8™ is a high speed, high voltage N-channel switch-mode power MOSFET. This 'FREDFET' version has a drain-source (body) diode that has been optimized for high reliability in ZVS phase shifted bridge and other circuits through reduced t_{rr}, soft recovery, and high recovery dv/dt capability. Low gate charge, high gain, and a greatly reduced ratio of C_{rss}/C_{iss} result in excellent noise immunity and low switching loss. The intrinsic gate resistance and capacitance of the poly-silicon gate structure help control di/dt during switching, resulting in low EMI and reliable paralleling, even when switching at very high frequency.



APT44F80B2 APT44F80L



FEATURES

- Fast switching with low EMI
- Low t_{rr} for high reliability
- Ultra low C_{rss} for improved noise immunity
- Low gate charge
- Avalanche energy rated
- RoHS compliant 

TYPICAL APPLICATIONS

- ZVS phase shifted and other full bridge
- Half bridge
- PFC and other boost converter
- Buck converter
- Single and two switch forward
- Flyback

Absolute Maximum Ratings

Symbol	Parameter	Ratings	Unit
I _D	Continuous Drain Current @ T _c = 25°C	47	A
	Continuous Drain Current @ T _c = 100°C	29	
I _{DM}	Pulsed Drain Current ^①	173	
V _{GS}	Gate - Source Voltage	±30	V
E _{AS}	Single Pulse Avalanche Energy ^②	1980	mJ
I _{AR}	Avalanche Current, Repetitive or Non-Repetitive	24	A

Thermal and Mechanical Characteristics

Symbol	Characteristic	Min	Typ	Max	Unit
P _D	Total Power Dissipation @ T _c = 25°C	-	-	1135	W
R _{θJC}	Junction to Case Thermal Resistance	-	-	.11	°C/W
R _{θCS}	Case to Sink Thermal Resistance, Flat, Greased Surface	-	.11	-	
T _J , T _{STG}	Operating and Storage Junction Temperature Range	-55	-	150	°C
T _L	Soldering Temperature for 10 Seconds (1.6mm from case)	-	-	300	
W _T	Package Weight	-	0.22	-	oz
		-	6.2	-	g
Torque	Mounting Torque (TO-264 Package), 4-40 or M3 screw	-	-	10	in·lbf
		-	-	1.1	N·m

Static Characteristics

$T_J = 25^\circ\text{C}$ unless otherwise specified

APT44F80B2_L

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
$V_{BR(DSS)}$	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu\text{A}$	800			V
$\Delta V_{BR(DSS)}/\Delta T_J$	Breakdown Voltage Temperature Coefficient	Reference to $25^\circ\text{C}, I_D = 250\mu\text{A}$		0.87		$^\circ\text{C}/\text{V}$
$R_{DS(on)}$	Drain-Source On Resistance ^③	$V_{GS} = 10V, I_D = 24\text{A}$		0.17	0.21	Ω
$V_{GS(th)}$	Gate-Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 2.5\text{mA}$	2.5	4	5	V
$\Delta V_{GS(th)}/\Delta T_J$	Threshold Voltage Temperature Coefficient			-10		$\text{mV}/^\circ\text{C}$
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 800\text{V}$ $V_{GS} = 0V$			250	μA
I_{GSS}	Gate-Source Leakage Current	$V_{GS} = \pm 30\text{V}$			± 100	nA

Dynamic Characteristics

$T_J = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
g_{fs}	Forward Transconductance	$V_{DS} = 50\text{V}, I_D = 24\text{A}$		43		S
C_{iss}	Input Capacitance			9330		
C_{rss}	Reverse Transfer Capacitance	$V_{GS} = 0V, V_{DS} = 25\text{V}$ $f = 1\text{MHz}$		160		
C_{oss}	Output Capacitance			930		pF
$C_{o(cr)}^{\text{(4)}}$	Effective Output Capacitance, Charge Related			440		
$C_{o(er)}^{\text{(5)}}$	Effective Output Capacitance, Energy Related	$V_{GS} = 0V, V_{DS} = 0\text{V}$ to 533V		220		
Q_g	Total Gate Charge			305		
Q_{gs}	Gate-Source Charge	$V_{GS} = 0$ to $10\text{V}, I_D = 24\text{A},$ $V_{DS} = 400\text{V}$		51		nC
Q_{gd}	Gate-Drain Charge			155		
$t_{d(on)}$	Turn-On Delay Time			55		
t_r	Current Rise Time			75		
$t_{d(off)}$	Turn-Off Delay Time	$V_{DD} = 400\text{V}, I_D = 24\text{A}$ $R_G = 4.7\Omega^{\text{(6)}}$, $V_{GG} = 15\text{V}$		230		
t_f	Current Fall Time			70		ns

Source-Drain Diode Characteristics

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
I_s	Continuous Source Current (Body Diode)	MOSFET symbol showing the integral reverse p-n junction diode (body diode)			47	A
I_{SM}	Pulsed Source Current (Body Diode) ^①				173	
V_{SD}	Diode Forward Voltage	$I_{SD} = 24\text{A}, T_J = 25^\circ\text{C}, V_{GS} = 0\text{V}$			1.2	V
t_{rr}	Reverse Recovery Time			320	370	nS
		$T_J = 25^\circ\text{C}$		590	710	
Q_{rr}	Reverse Recovery Charge	$I_{SD} = 24\text{A}^{\text{(3)}}$ $di_{SD}/dt = 100\text{A}/\mu\text{s}$ $V_{DD} = 100\text{V}$		1.91		μC
I_{rm}	Reverse Recovery Current	$T_J = 25^\circ\text{C}$		5.18		
		$T_J = 125^\circ\text{C}$		12.1		A
		$T_J = 25^\circ\text{C}$		18.1		
dv/dt	Peak Recovery dv/dt	$I_{SD} \leq 24\text{A}, di/dt \leq 1000\text{A}/\mu\text{s}, V_{DD} = 400\text{V},$ $T_J = 125^\circ\text{C}$			25	V/ns

① Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature.

② Starting at $T_J = 25^\circ\text{C}$, $L = 6.9\text{mH}$, $R_G = 25\Omega$, $I_{AS} = 24\text{A}$.

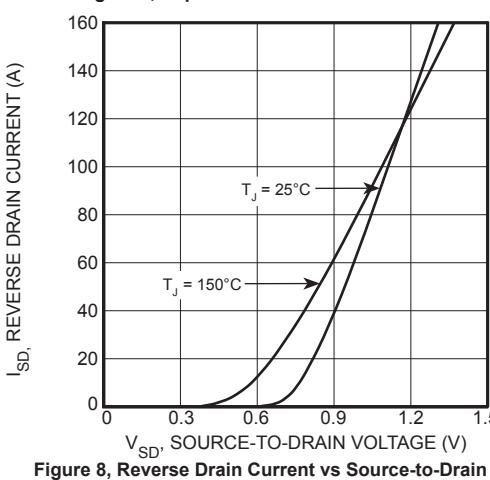
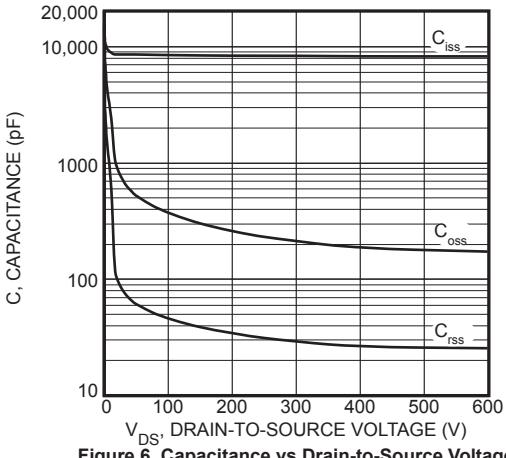
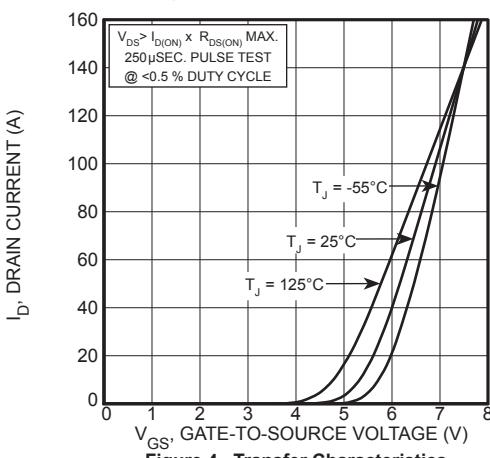
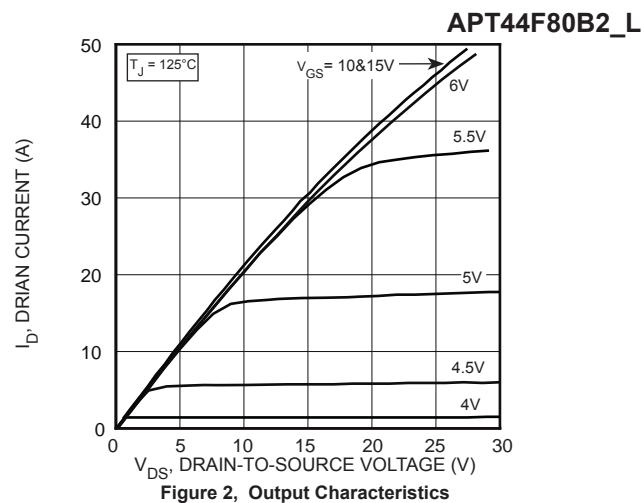
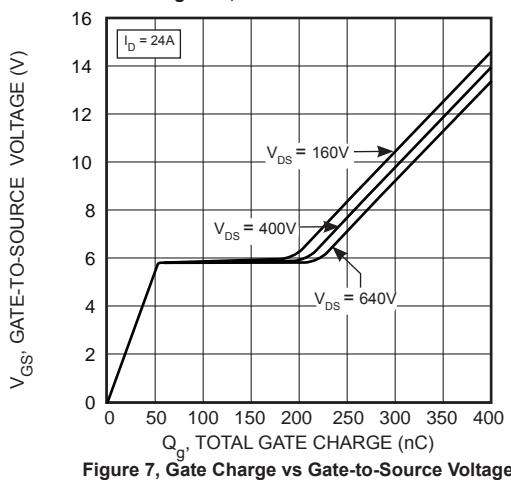
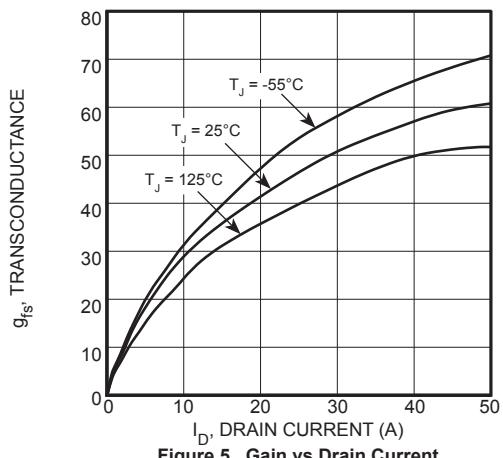
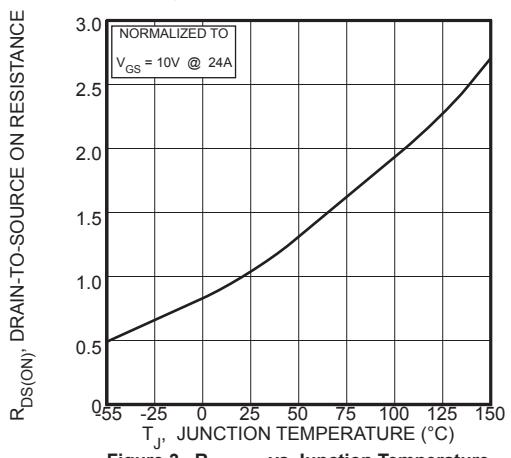
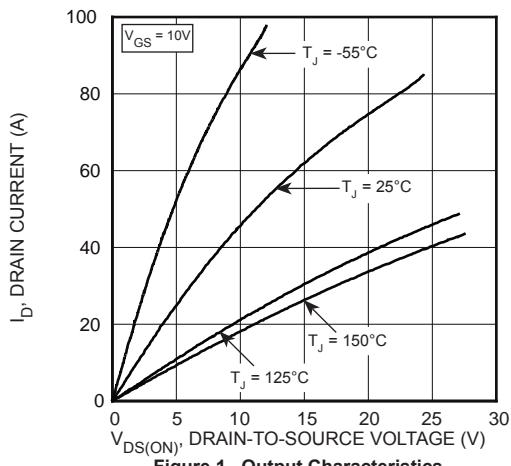
③ Pulse test: Pulse Width < 380 μs , duty cycle < 2%.

④ $C_{o(cr)}$ is defined as a fixed capacitance with the same stored charge as C_{oss} with $V_{DS} = 67\%$ of $V_{(BR)DSS}$.

⑤ $C_{o(er)}$ is defined as a fixed capacitance with the same stored energy as C_{oss} with $V_{DS} = 67\%$ of $V_{(BR)DSS}$. To calculate $C_{o(er)}$ for any value of V_{DS} less than $V_{(BR)DSS}$, use this equation: $C_{o(er)} = -8.32E-8/V_{DS}^2 + 3.49E-8/V_{DS} + 1.30E-10$.

⑥ R_G is external gate resistance, not including internal gate resistance or gate driver impedance. (MIC4452)

Microsemi reserves the right to change, without notice, the specifications and information contained herein.



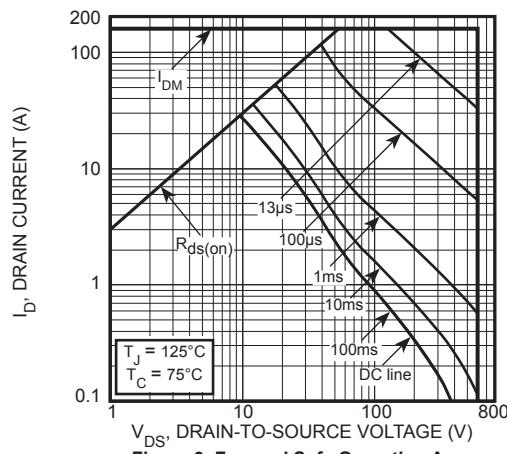


Figure 9, Forward Safe Operating Area

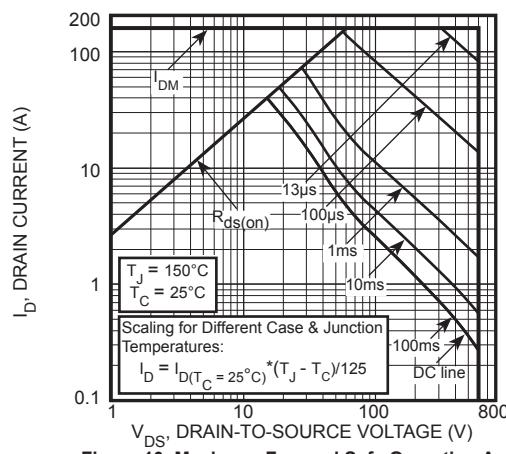


Figure 10, Maximum Forward Safe Operating Area

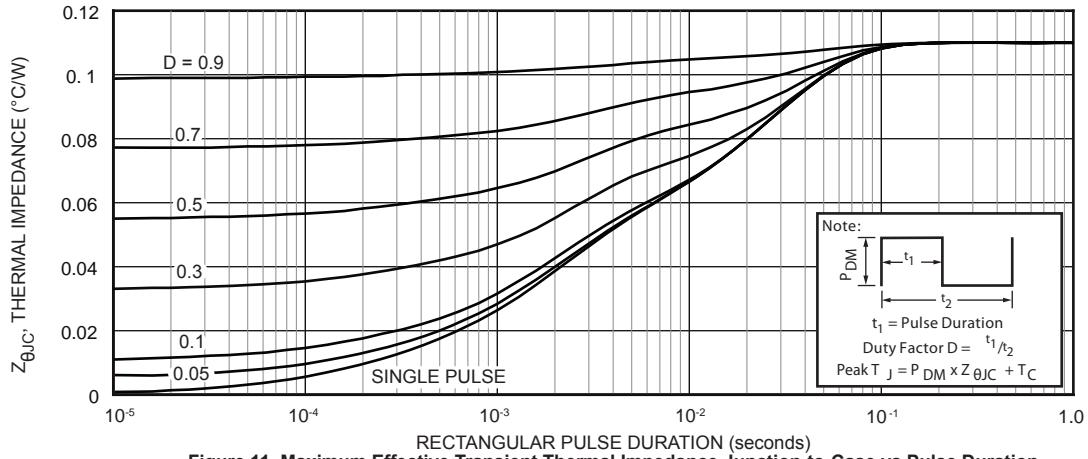
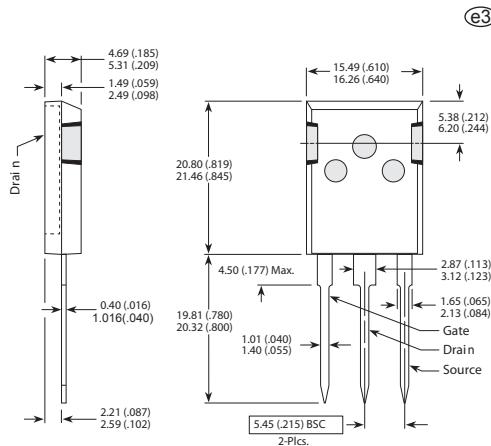
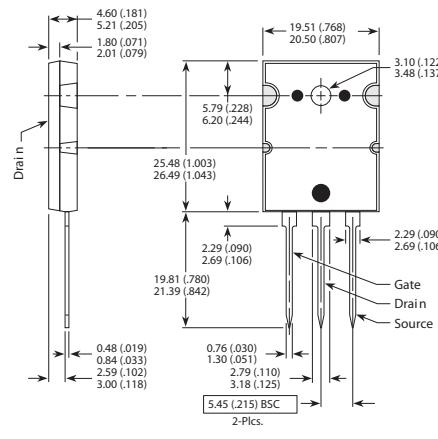


Figure 11. Maximum Effective Transient Thermal Impedance Junction-to-Case vs Pulse Duration

T-MAX™ (B2) Package Outline

Dimensions in Millimeters (Inches)

TO-264 (L) Package Outline

Dimensions in Millimeters (Inches)